

Application No. 09/773,674
Amendment November 18, 2005
Reply to Office Action of July 14, 2005

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Amendments to the Claims

This listing of claims will replace all prior versions, and listing, of claims in the application:

Claims 1- 38 (canceled)

39. (previously presented) A method of forming a test slide for microscopes, comprising the steps of:

forming a master test pattern on an information carrier for an injection molding device, said test pattern including patterns of known size and shape;

(i) inserting said information carrier into said injection molding device;

(ii) cycling said injection molding device to inject liquefied resin into contact with said information carrier and to cool said resin to form a plastic carrier with said test pattern formed in one surface; and

(iii) removing said plastic carrier from said injection molding machine.

40. (previously presented) The method of claim 39 wherein said information carrier comprises at least two master test patterns and further comprising step (v) wherein said plastic carrier is cut to separate each of the test patterns thereon.

41. (previously presented) The method of claim 40 wherein said plastic carrier is cut to form conventional sized microscope slides with said test patterns being located at an image area thereon.

42. (previously presented) The method of claim 39 wherein said master test pattern comprises a collection of reference images.

43. (previously presented) The method of claim 42 wherein said images of said reference collection have been originally obtained from visible light microscopy.

44. (previously presented) The method of claim 42 wherein said images of said reference collection have been originally obtained from scanning electron microscopy.

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45. (previously presented) The method of claim 42 wherein said images of said reference collection comprise a montage of images.

46. (previously presented) The method of claim 42 wherein said master test pattern further comprises a grid and where said images are arranged in said grid.

47. (previously presented) The method of claim 39 further comprising step (v) applying a planar layer of thin film material to at least a portion of said one surface.

48. (previously presented) A method of claim 47 wherein said layer is applied to said one surface in areas including image features comprising recesses in said surface such that optical interference in said layer produces colors discernable to a viewer.

49. (previously presented) A method of forming a test slide of microscopes, comprising the steps of;

(i) forming a master test pattern on an information carrier for a mold, said test pattern including patterns of known size and shape;

(ii) inserting said information carrier into a mold;

(iii) adding a substrate material to said mold to contact said information carrier and setting said substrate material to form a carrier with said test pattern formed in one surface; and

(iv) removing said carrier from said mold.